

# New Conducting AFM Probes for Dynamic Electrical Measurements

**Larissa Shabratova**  
**(Marketing Manager MIKROMASCH)**  
**and**  
**Pavel Malyshkin**  
**(Technical specialist MikroMasch)**

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AFM-based electric methods are used for the characterization of local conductivity/resistance, surface potential, capacitance, dielectric constants, distribution and orientation of molecular dipoles, the presence of localized surface charges, etc.

The parameters of conducting probes for electrical measurements are usually a compromise between spatial resolution and detection sensitivity in measurements of a particular electric property. However, this compromise can be shifted towards one purpose or another.

**Appropriate parameters of the probe tip are essential for optimization of imaging and quantitative measurements. Therefore, Mikromasch has designed new types of conducting AFM probes suitable for dynamic electrical SPM applications that will ensure best results.**



Contact info: [infos@aperesearch.com](mailto:infos@aperesearch.com)  
Tel: 040 3757905

